

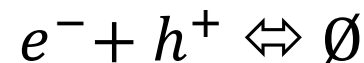
# Announcements

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- Readings:
  - Chapter 1
  - Chapter 2 (2.1-2.10)
- Multisim tutorial: if enough interest (GoPost)
- Office Hour after this lecture:
  - Wednesday 2:00-3:00 pm @ EE 218

# Intrinsic Carrier Concentration

- Can think of holes and electrons like chemical species.

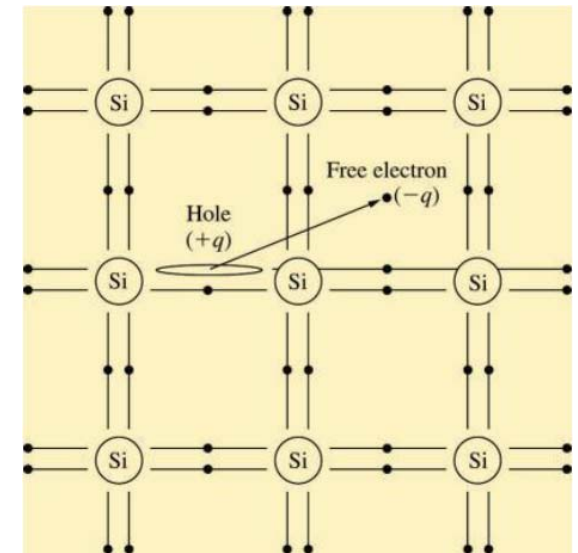


- In equilibrium, the ratio of the product of the concentrations of the reactants to the product of the concentrations of the products is equal to an equilibrium constant

$$\frac{pn}{4N} = K$$

- $p$  : concentration of holes
- $n$  : concentration of electrons
- $N$  : concentration of atoms

$$pn = 4NK \equiv n_i^2$$



# Intrinsic Carrier Concentration

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- Intrinsic carrier concentration  $n_i^2$  only depends on **temperature** ( $T$ ) and **material** ( $B, E_G$ )

$$n_i^2 = BT^3 \exp\left(-\frac{E_G}{kT}\right) \text{ cm}^{-6}$$

- $E_G$  : band gap energy of the **material**, in eV.  $E_G$  is the minimum energy to break the covalent bond and excite a free electron.
- $k$  : Boltzmann's constant,  $8.62 \times 10^{-5} \text{ eV / K}$
- $T$  : Absolute **temperature** in K (Kelvin)
- $B$  : **material**-dependent parameter

$$1 \text{ eV} = 1.6 \times 10^{-19} \text{ J}$$

$$\text{K} = ^\circ\text{C} + 273.15$$

# Intrinsic Carrier Concentration

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- Example: Calculate intrinsic carrier concentration of Si at 300 K (RT) and 1200 K .

$$n_i^2 = BT^3 \exp\left(-\frac{E_G}{kT}\right) \text{ cm}^{-6}$$

- For Si:  $E_G = 1.12 \text{ eV}$ ,  $B_{\text{Si}} = 2.23 \times 10^{31} \text{ K}^{-3} \text{ cm}^{-6}$
- At 300 K,  $n_i = 1.0 \times 10^{10} \text{ cm}^{-3}$
- At 1200 K,  $n_i = 1.26 \times 10^{18} \text{ cm}^{-3}$
- Silicon valence electron density:  $\sim 10^{23} \text{ cm}^{-3}$
- Fraction of bonds broken to excite a free electron
  - $\sim 10^{-13}$  for  $T = 300 \text{ K}$
  - $\sim 10^{-5}$  for  $T = 1200 \text{ K}$

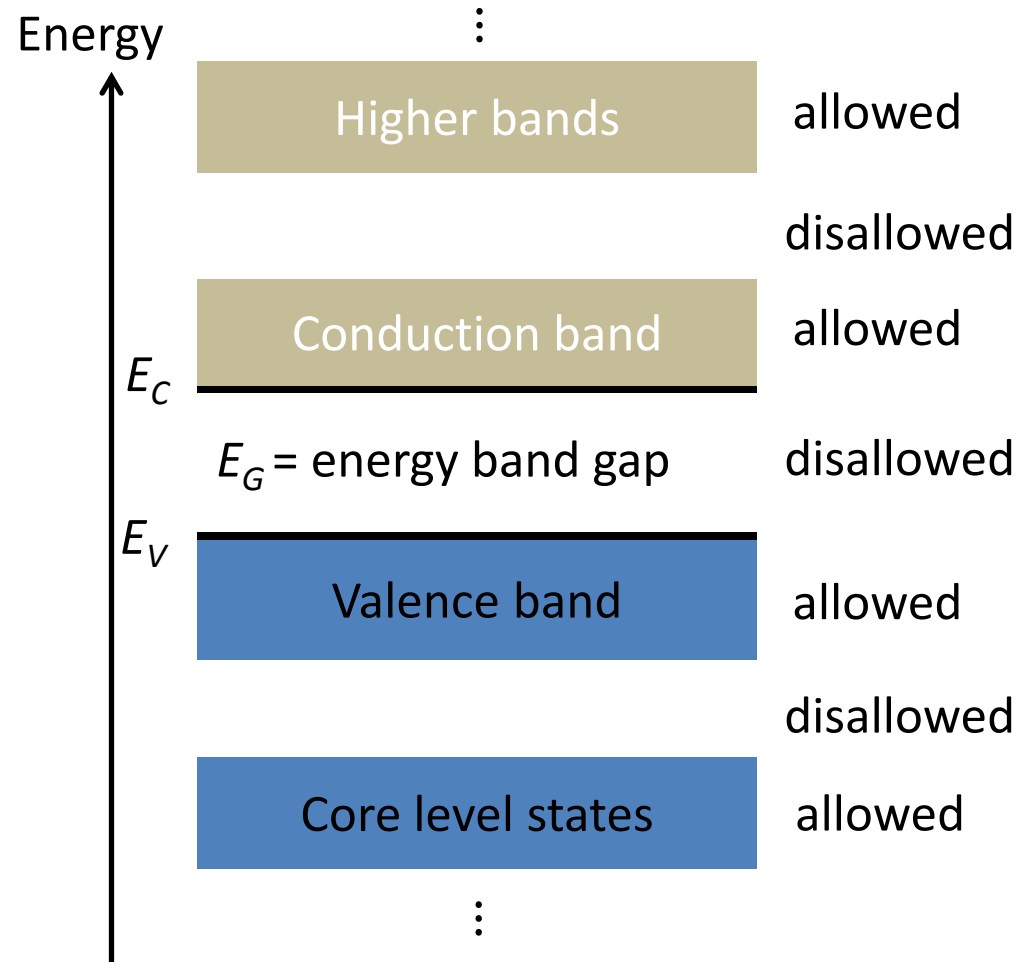
8 orders of magnitude!

Small fraction!

# Energy Band Model of Semiconductors

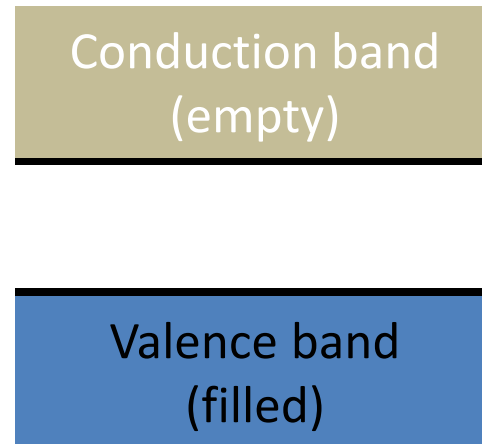
## Electron States

- Quantum Physics: 1 electron occupies 1 state
- Crystal Structure of a material produces ranges of **allowed** and **disallowed** energy states for electrons.
- Electrons fill allowed states: starting with the lowest energies and filling upwards.

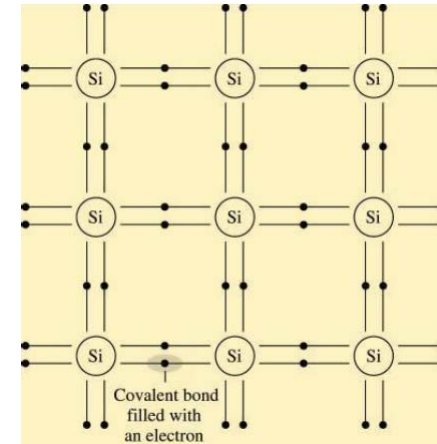


# Energy Band Model of Semiconductors

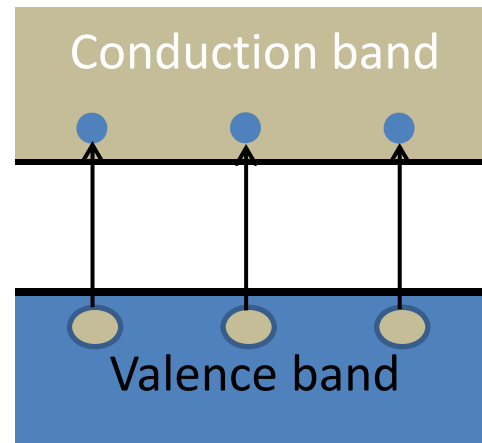
$T = 0 \text{ K}$



No free carriers

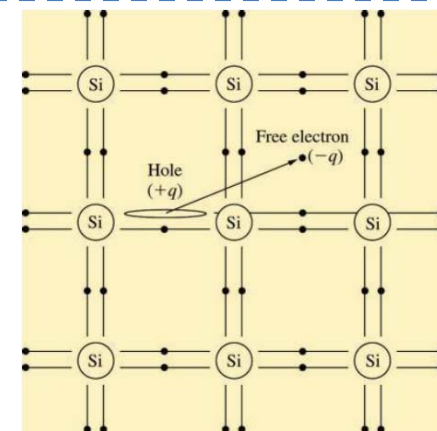


$T > 0 \text{ K}$



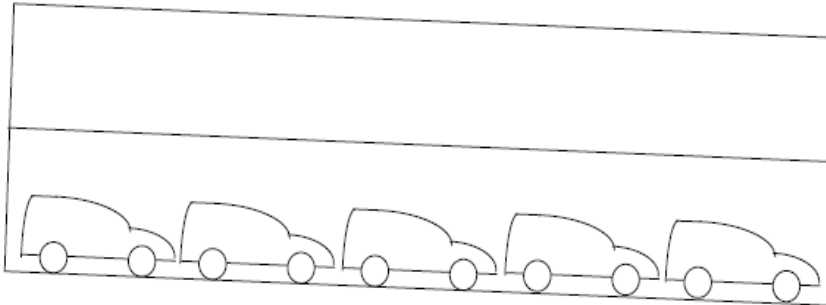
electrons

holes



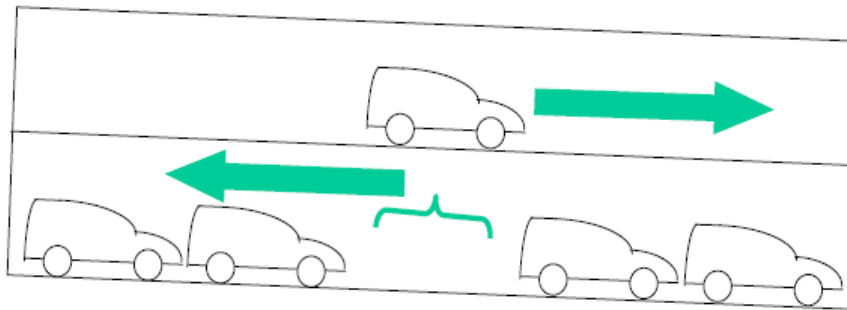
# Conduction – Parking Lot Analogy

- Neither empty bands nor full bands contribute to conduction
- **Conduction arises from partially filled bands** (electrons in conduction band and holes in valence bands)



At  $T = 0 \text{ K}$

- Upper floor empty – no traffic
- Lower floor full – no traffic



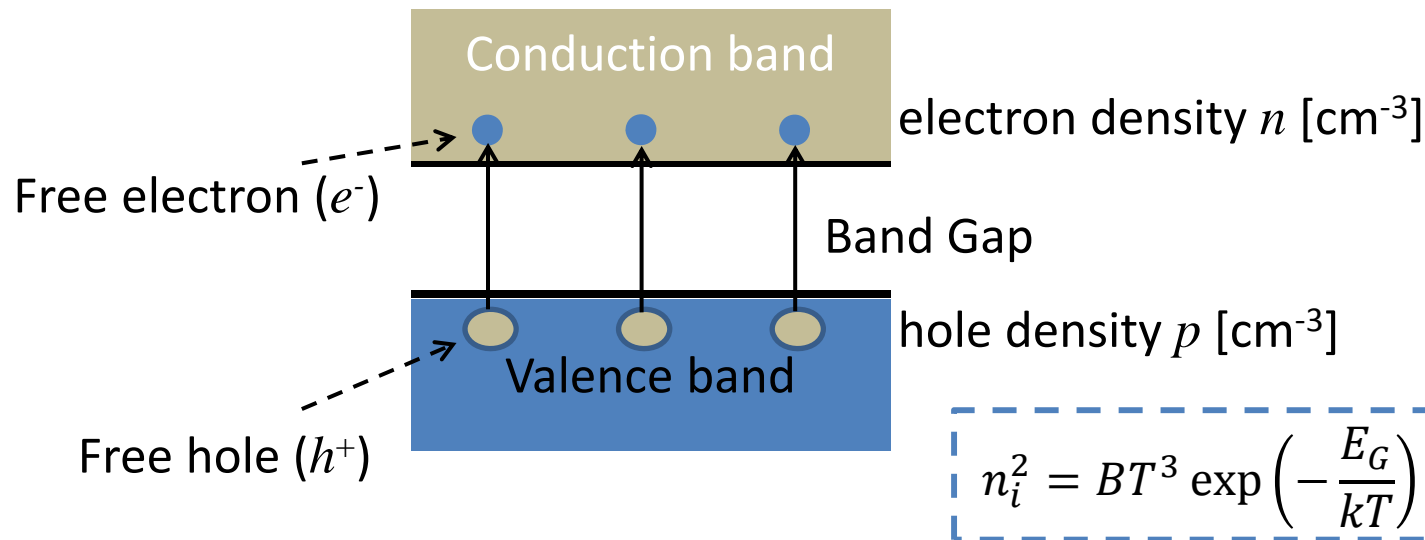
At  $T > 0 \text{ K}$

- One car move to the top floor; leaves one vacancy in the lower floor
- Both the car and the vacancy can move – traffic

Car – electron; vacancy – hole; traffic – conduction

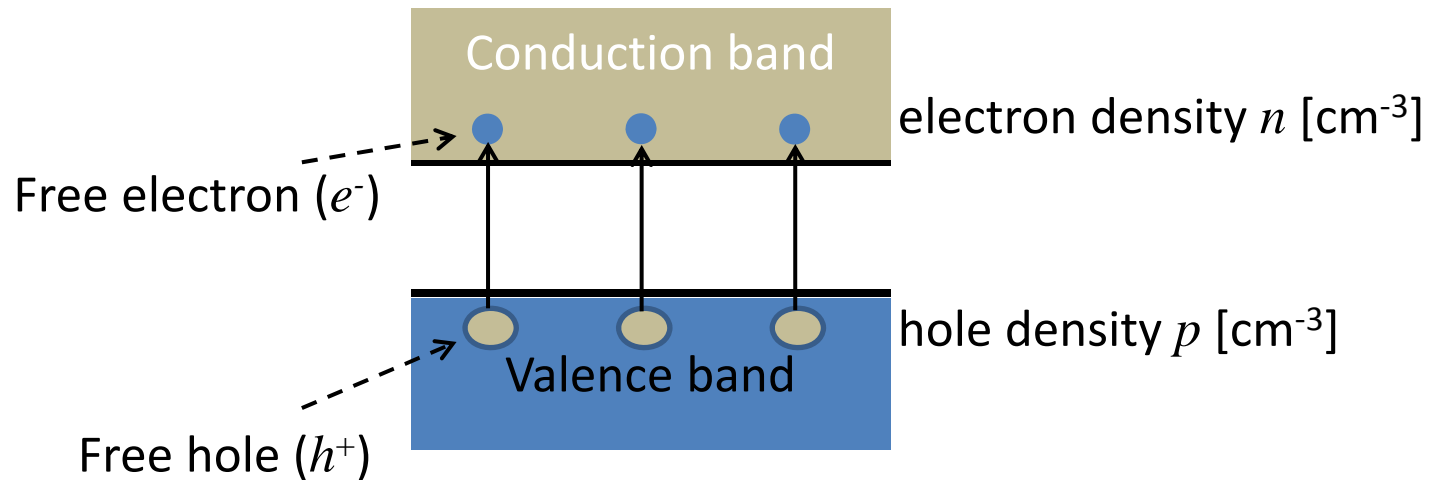
Upper floor – conduction band; lower floor – valence band

# Energy Band Model – Intrinsic Silicon



- In intrinsic silicon, there's one free hole per excited free electron =>  $n = p$ . By definition,  $n = p = n_i$  (Intrinsic carrier density)
- $n_i$  depends only on temperature and material
  - Higher  $T$ ,  $n_i$  higher (more thermal energy, easier to excite electrons)
  - Larger Band gap,  $n_i$  lower (electrons harder to “jump” to conduction band)

# Conduction in Intrinsic Silicon



- Conduction is due to **both electrons and holes** in a semiconductor

$$\sigma = qn\mu_n + qp\mu_p$$

Previously, we had only  $\sigma = qn\mu_n$

Electron density  $\leftarrow$   $qn\mu_n$   
 Electron mobility  $\leftarrow$   $\mu_n$   
 Hole density  $\leftarrow$   $qp\mu_p$   
 Hole mobility  $\leftarrow$   $\mu_p$

$\mu_n > \mu_p$

- Intrinsic silicon:  $\sigma = q(\mu_n + \mu_p)n_i$



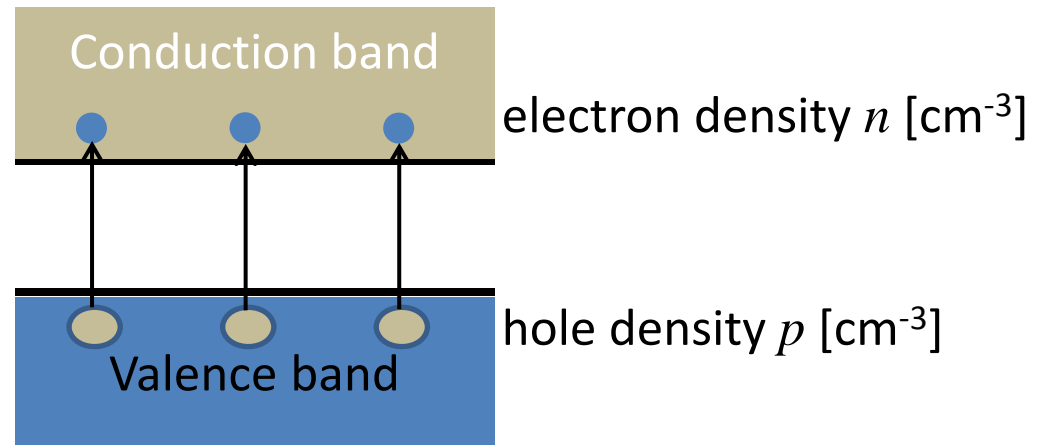
# Conduction in Intrinsic Silicon

$$J_n = qn\mu_n E$$

$$J_p = qp\mu_p E$$

$$J = J_n + J_p$$

$$J = \sigma E$$



$$\sigma = q(\mu_n n + \mu_p p)$$

Intrinsic Si @ RT:  $\sigma = q(\mu_n + \mu_p)n_i$

$$= (1.6 \times 10^{19} \text{C}) \left( [1000 + 400] \frac{\text{cm}^2}{\text{Vs}} \right) (1 \times 10^{10} \text{cm}^{-3})$$
$$= 2.2 \times 10^{-6} \text{ S/cm}$$

# Extrinsic Semiconductor

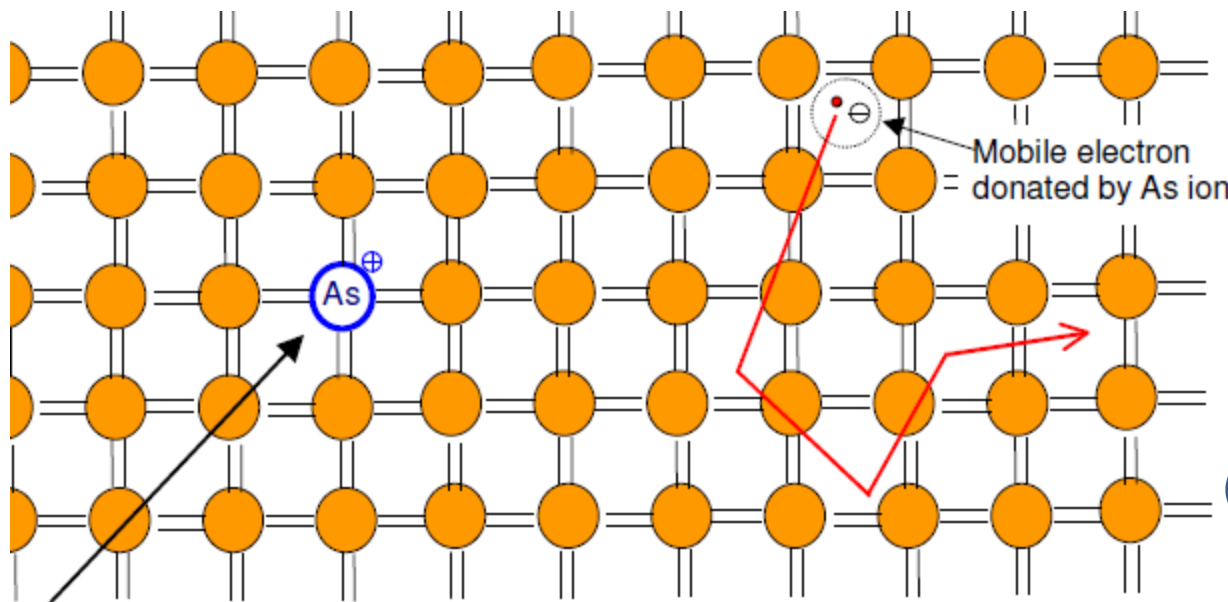
- Conductivity in intrinsic silicon is low in normal conditions (insulator).
- Trace amounts of impurities (**dopants**) are added to adjust the conductivity.
- Two types of substitutional dopants:
  - Group V elements, P, As, Sb  
(**donor**)
  - Group III elements, B, Al, Ga, In  
(**acceptor**)

ES:

IIIA		IVA		VA		VIA					
5	10.811 <b>B</b> Boron	6	12.01115 <b>C</b> Carbon	7	14.0067 <b>N</b> Nitrogen	8	15.9994 <b>O</b> Oxygen				
13	26.9815 <b>Al</b> Aluminum	14	28.086 <b>Si</b> Silicon	15	30.9738 <b>P</b> Phosphorus	16	32.064 <b>S</b> Sulfur				
IIB		30	65.37 <b>Zn</b> Zinc	31	69.72 <b>Ga</b> Gallium	32	72.59 <b>Ge</b> Germanium	33	74.922 <b>As</b> Arsenic	34	78.96 <b>Se</b> Selenium
48	112.40 <b>Cd</b> Cadmium	49	114.82 <b>In</b> Indium	50	118.69 <b>Sn</b> Tin	51	121.75 <b>Sb</b> Antimony	52	127.60 <b>Te</b> Tellurium		
80	200.59 <b>Hg</b> Mercury	81	204.37 <b>Tl</b> Thallium	82	207.19 <b>Pb</b> Lead	83	208.980 <b>Bi</b> Bismuth	84	(210) <b>Po</b> Polonium		

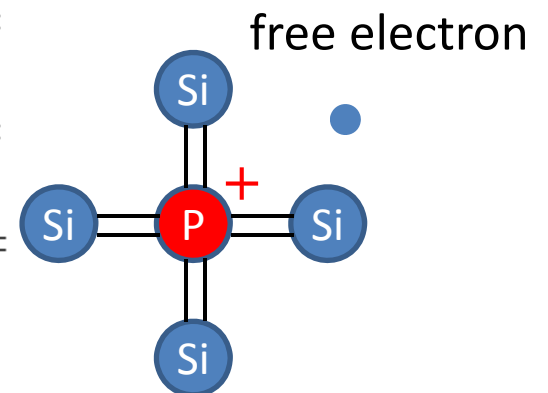
# Extrinsic Semiconductor - Donor

- Group V elements (**donors**)
  - Have one more outer electrons than Si (5 vs. 4)
  - Can **donate** one free electron, and become positively charged (charge neutrality condition).



Immobile (stuck) positively charged arsenic ion after 5<sup>th</sup> electron left

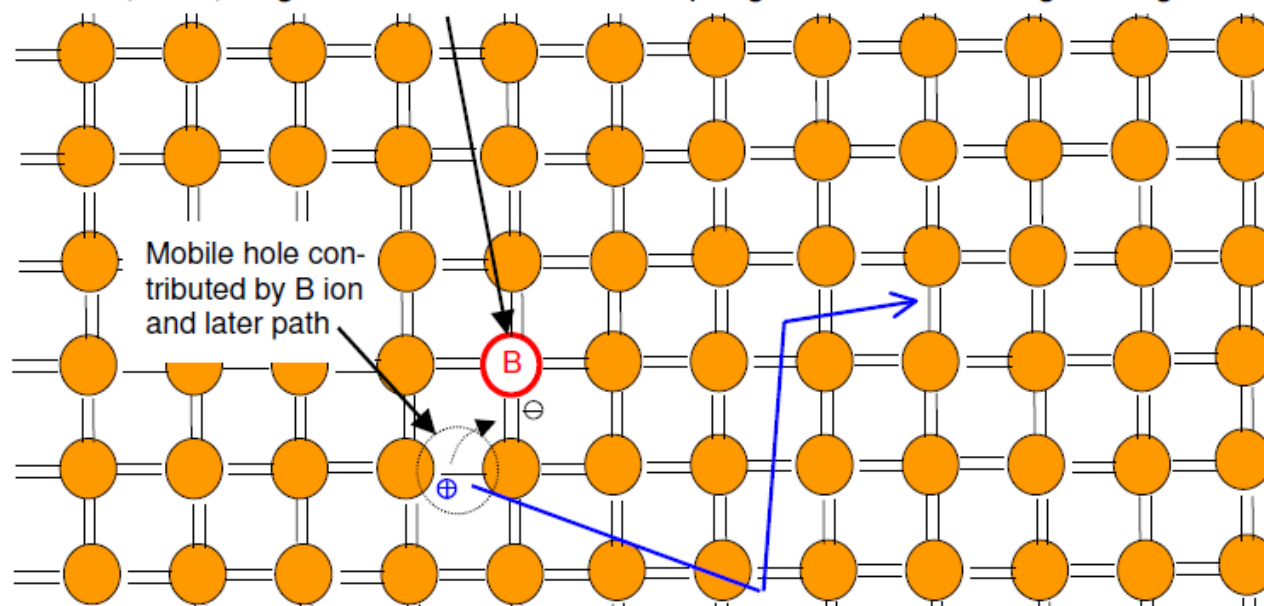
$N_D$  = donor density  
[cm<sup>-3</sup>] (**positive**,  
**fixed** charge)



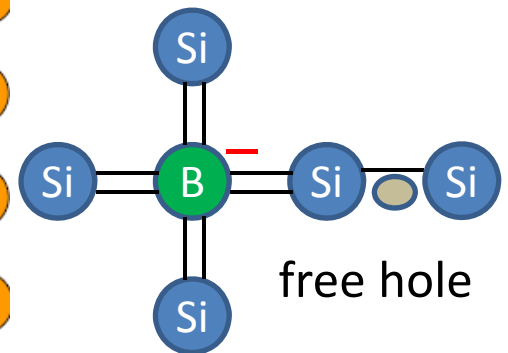
# Extrinsic Semiconductor - Acceptor

- Group III elements (**acceptors**)
  - Have one less outer electrons than Si (3 vs. 4)
  - Can **accept** one electron (donate a hole), and become negatively charged (charge neutrality condition).

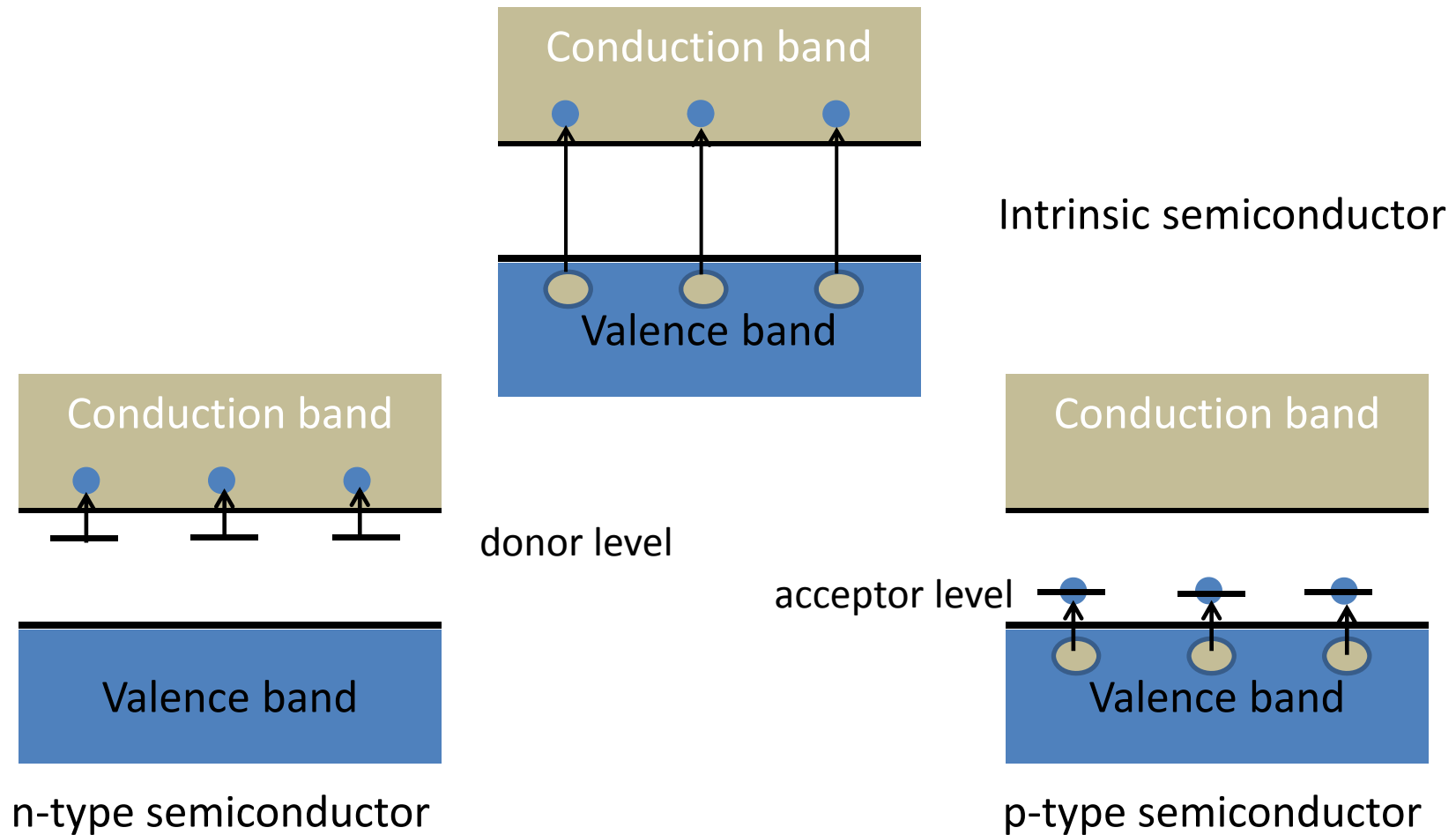
Immobile (stuck) negative boron ion after accepting electron from neighboring bond



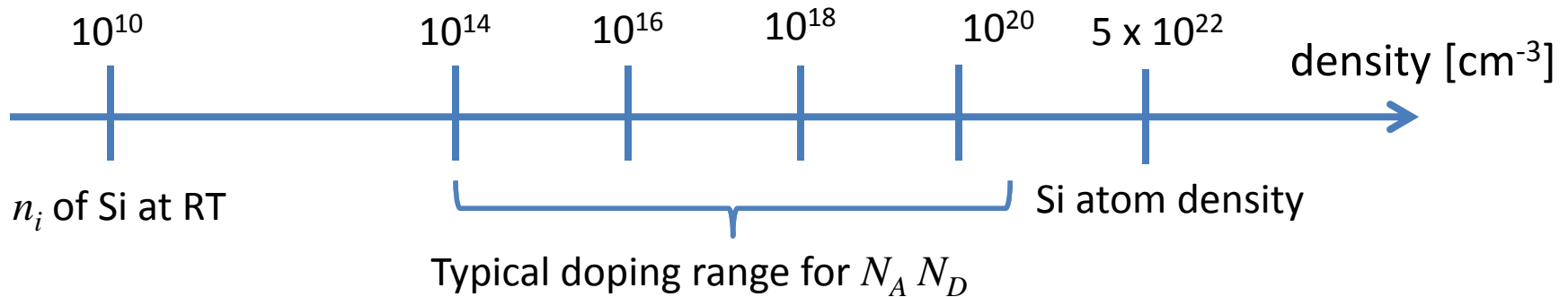
$N_A$  = acceptor density [ $\text{cm}^{-3}$ ]  
(**negative**, **fixed** charge)



# Conduction in Intrinsic Silicon



# Typical Doping Range



- Typical doping range:
  - Minimal chemical / mechanical changes (trace impurity)
  - Major changes in electrical conductivity

# Extrinsic Semiconductors

## – Carrier Density

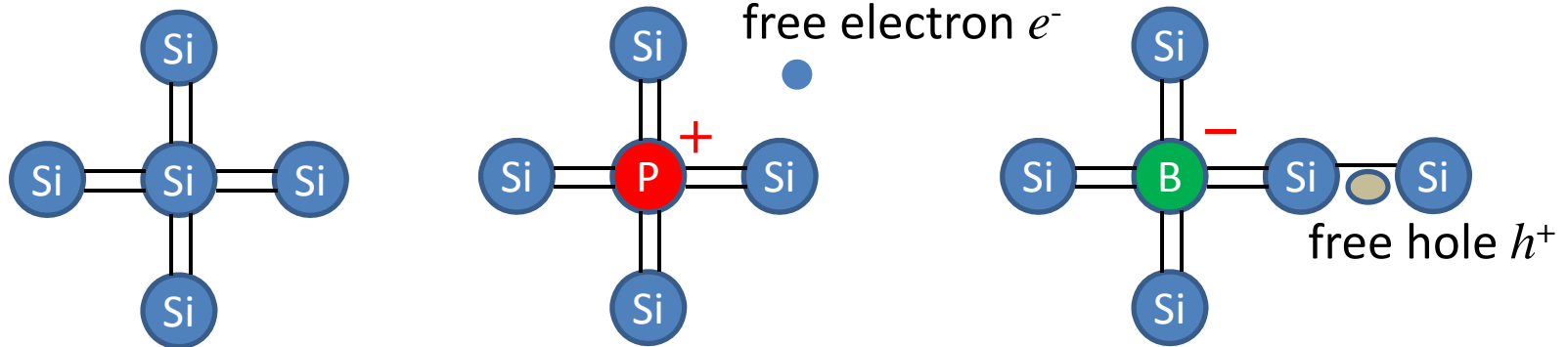
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- The carrier density ( $n, p$ ) in extrinsic semiconductors is governed by two laws:
  - Law of Mass Action (equilibrium condition):

$$np = n_i^2$$

- Charge Neutrality Condition:

$$N_D + p - N_A - n = 0$$



# Extrinsic Semiconductors

## – Carrier Density (*n*-type)

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- Silicon doped with donors with density  $N_D$  ( $N_A = 0$ )

- Solve  $np = n_i^2$  and  $N_D + p - n = 0$

- Eliminate  $p$ :

$$N_D + \frac{n_i^2}{n} - n = 0 \Rightarrow n^2 - nN_D - n_i^2 = 0$$

- Solve:  $n = \frac{N_D + \sqrt{N_D^2 + 4n_i^2}}{2}, p = \frac{n_i^2}{n}$

Negative solution tossed out

- Most of the time:  $N_D \gg n_i$ , thus  $n \cong N_D, p \cong \frac{n_i^2}{N_D} \Rightarrow n \gg n_i \gg p$ , the semiconductor is called “*n*-type”

- Electrons: **majority** carrier; Holes: **minority** carrier

# Extrinsic Semiconductors

## – Carrier Density (*p*-type)

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- Silicon doped with acceptors with density  $N_A$  ( $N_D = 0$ )
  - Solve  $np = n_i^2$  and  $p - N_A - n = 0$
  - Eliminate  $n$ :

$$p - N_A - \frac{n_i^2}{p} = 0 \Rightarrow p^2 - pN_A - n_i^2 = 0$$

Negative solution tossed out

$$\text{– Solve: } p = \frac{N_A + \sqrt{N_A^2 + 4n_i^2}}{2}, n = \frac{n_i^2}{p}$$

- Most of the time:  $N_A \gg n_i$ , thus  $p \cong N_A, n \cong \frac{n_i^2}{N_A} \Rightarrow p \gg n_i \gg n$ , the semiconductor is called “*p*-type”
- Holes: **majority** carrier; Electrons: **minority** carrier